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SERIAL NUMBER 10/619,933	FILING DATE 07/15/2003 RULE	CLASS 250	GROUP ART UNIT 2881	ATTORNEY DOCKET NO. OST-031107	
<b>APPLICANTS</b> Thorsten Lower, Brachtal, GERMANY;  <b>** CONTINUING DATA *****</b> <i>NONE</i> <b>** FOREIGN APPLICATIONS *****</b> GERMANY 102 32 230.9 07/17/2002 <b>IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** SMALL ENTITY **</b> <b>** 11/24/2003</b>					
Foreign Priority claimed 35 USC 119 (a-d) conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance Verified and Acknowledged Examiner's Signature <i>[Signature]</i> Initials <i>[Initials]</i>	STATE OR COUNTRY GERMANY	SHEETS DRAWING 5	TOTAL CLAIMS 35	INDEPENDENT CLAIMS 1
<b>ADDRESS</b> 22876 FACTOR & LAKE, LTD 1327 W. WASHINGTON BLVD. SUITE 5G/H CHICAGO, IL 60607					
<b>TITLE</b> Method for measuring the intensity profile of an electron beam, in particular a beam of an electron-beam machining device, and/or for measuring an optical system for an electron beam and/or for adjusting an optical system for an electron beam, measuring structure for such a method and electron-beam machining device					
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